

<b>Notice of References Cited</b>	Application/Control No. 10/824,926	Applicant(s)/Patent Under Reexamination TAJIMA ET AL.	
	Examiner Kezhen Shen	Art Unit <del>2627</del> 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,470,628	11-1995	Tominaga et al.	428/64.4
*	B	US-5,569,517	10-1996	Tominaga et al.	428/64.1
*	C	US-5,503,890	04-1996	Jung, Hee T.	428/64.1
*	D	US-5,516,568	05-1996	Jung, Hee-Tae	428/64.1
*	E	US-5,610,879	03-1997	Moriya et al.	369/13.24
*	F	US-2002/0168588 A1	11-2002	Takamori et al.	430/270.15
*	G	US-6,246,656 B1	06-2001	Kawakubo et al.	369/112.23
*	H	US-6,071,587	06-2000	Yoshinari et al.	428/64.1
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.